Poef Rageevan Chamod 2311 Roll No.....

Name of Examination: END-SEMESTER EXAMINATION, 22 November 2023

Branch: Dual Degree Integrated E&CE, 4th Year

Course Name: Device Modeling for Circuit Simulation

Time: 3 Hours

Semester : 7th Course Code : EC-631 Maximum Marks: 50

11/2823

Room: F1/F2/F3, Session B: 2.30pm to 5.30pm

Note:

i) All questions are compulsory. Assume any missing data. ii) Give short answers for Q1. iii) Attempt all parts of any question at one place & in sequence.

| Q# | | Questions | Marks | СО |
|----|-------|---|-------|--------|
| 1. | (i) | Design a MOSFET for attaining minimal threshold voltage? | 2 | |
| | (ii) | Give significance and meaning of Early effect and high level injection in electronic diodes and transistors? | 2 | CO1 |
| | (iii) | Write SPICE commands for a Resistor of $2k\Omega$, an Inductor of 2nH, a linearly graded pn junction and an npn BJT? | 2 | CO3 |
| | (iv) | Drawing the energy band diagrams specify: onset of inversion and strong inversion conditions for a MOSFET. Compute different parameters from these energy band diagrams. | 2 | |
| | (v) | Enlist the different nomenclatures for high speed FETs and give the working principle of these transistors. | 2 | |
| 2. | (i) | Evaluate the performance of a BJT and a MOSFET in a tabular way from fabrication, working and applications, point of view. | .2 | CO4 |
| | (ii) | Draw the electrical equivalent model of a pn junction diode. Hence develop an Ebers Moll ac equivalent circuit model of a BJT and highlight its importance. | 3 | CO2 |
| 3 | (iii) | At 300K, let the normal (β_N) and inverse (β_I) mode common emitter current gains be 100 and 2, respectively, for a BJT. For an emitter bias of 0.7V, the normal mode emitter current is 5mA. Determine the emitter (I_{ES}) and collector (I_{CS}) saturation currents. It is known that $\alpha_N I_{ES} = \alpha_I I_{CS}$. | 5 | CO4 |
| 3. | i) | Design a step $p+n$ junction diode at room temp to attain a built- in potential of 0.35V. | 5 | CO2 |
| | ii) | Analyze which of the following MOSFETs, MODFETs and MESFETs is the most important transistor and justify it? | 5 | CO4 |
| 4. | i) | Derive a relationship to show the effect of charge sharing on threshold voltage in short channel MOSFETs. How is threshold voltage varied in a narrow channel device? | 5 | CO2 |
| | ii) | Develop an electrical equivalent model of a MOSFET. Enlist reasons why such a model is essential for semiconductor devices and circuit simulation? | 5 | CO1 |
| | | Page 1/2 | | P.T.O. |

| 5. | i) | If input pulse signal is of 0V & 1V initial and final values, and rise & fall times are 2ns, respectively; initial delay can vary from 5 to 10ns, pulse width is 20ns and pulse period is 40ns. Write down the SPICE netlist for transient analysis till 100ns of a CMOS inverter driving a capacitive load of 0.1pF. Draw the circuit, the expected input and output waveforms. Let CMOS technology node be 90nm, use 5times the minimum dimensions of transistors and supply voltage 1V. | 5 | | | | |
|----------|-----|---|---|-----|--|--|--|
| | ii) | Design and analyze a MESFET to work in depletion mode. | 5 | CO4 | | | |
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 $DATA: \varepsilon_o = 8.854 \times 10^{-12} F / m, \varepsilon_{ox} = 4, \varepsilon_{Si} = 12, n_i = 1.5 \times 10^{16} m^{-3}, k = 1.38 \times 10^{-23} J / K,$ $R = (np - n_i^2) / [\tau_n \{p + n_i \exp((-(E_i - E_i)) / kT)\} + \tau_p \{n + n_i \exp((E_i - E_i) / kT)\}]$